

PART NO. MVR0603-240E0R2

1. Electrical Specification

1-1 Test condition

Varistor voltage In = 1 mA DC Leakage current Vdc = 24 V DC

Maximum clamping voltage Ic = 1 A

Rated peak single pulse transient current $8/20 \mu s$ waveform, +/- each 1 time induce

Capacitance 10/1000 μ s waveform Insulation resistance after reflow soldering f = 1MHz, Vrms = 0.5 V

Soldering paste : Tamura (Japan) RMA-20-21L

Stencil : SUS, 120 $\,\mu\mathrm{m}$ thickness

Reflow soldering condition Pad size : 0.8 (Width) x 0.9 (Length)

0.8 (Distance between pads)

Soldering profile : 260 ± 5 °C, 5 sec.

1-2 Electrical specification

Maximum allowable continuous DC voltage	24	V	
trigger voltage / Varistor voltage / breakdown voltage	110-130	V	
Maximum clamping voltage	250	V	Maximum
Rated peak single pulse transient current	1	Α	Maximum
Nonlinearity coefficient	> 12		
Leakage current at continuous DC voltage	< 0.1	μ A	
Response time	< 0.5	ns	
Varistor voltage temperature coefficient	< 0.05	%/℃	
Capacitance measured at 1MHz	0.2	pF	Typical
Capacitance tolerance	± 30	%	
Insulation resistance after reflow soldering on PCB	> 10	$\mathbf{M}\Omega$	
Operating ambient temperature	-55 to +125	${\mathbb C}$	
Storage temperature	-55 to +125	${\mathbb C}$	

1-3 Reliability testing procedures

Reliability parameter	Test	Test methods and remarks	Test requirement	
Pulse current capability	Imax 8/20 μs	IEC 1051-1, Test 4.5. 10 pulses in the same direction at 2 pulses per minute at maximum peak current	d Vn /Vn ≤ 10% no visible damage	
Electrostatic discharge capability	ESD C=150 pF, R=330 Ω	Each 10 times in positive/negative direction in 10 sec at 8KV contact discharge (Level 4)	d Vn /Vn ≤ 10% no visible damage	
Environmenta I reliability	Thermal shock	IEC 68-2-14 Condition for 1 cycle Step 1 : Min40℃, 30±3 min. Step 2 : Max. +125℃, 30±3 min. Number of cycles: 30 times	d Vn /Vn ≤ 5% no visible damage	
	Low temperature	Harmser or cycles: 50 times $\overline{\text{IEC }68\text{-}2\text{-}1}$ Place the chip at -40±5°C for 1000± 12hrs. Remove and place for 24±2hrs at room temp. condition, then measure	d Vn /Vn ≤ 5% no visible damage	
	High temperature	IEC 68-2-2 Place the chip at 125±5℃ for 1000± 24hrs. Remove and place for 24±2hrs at room temp. condition, then measure	d Vn /Vn ≤ 5% no visible damage	
	Heat resistance	IEC 68-2-3 Apply the rated voltage for $1000\pm48 hrs$ at $85\pm3\%$. Remove and place for $24\pm2 hrs$ at room temp. condition, then measure	d Vn /Vn ≤ 5% no visible damage	
	Humidity resistance	$\frac{IEC~68\text{-}2\text{-}30}{\text{Place the chip at }40\pm2\%~\text{and }90\text{ to }95\%}$ humidity for $1000\pm24\text{hrs}$. Remove and place for $24\pm2\text{hrs}$ at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage	
	Pressure cooker test	Place the chip at 2 atm, 120℃, 85%RH for 60 hrs. Remove and place for 24± 2hrs at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage	
	Operating life	Apply the rated voltage for 1000±48hrs at 125±3℃. Remove and place for 24±2hrs at room temp. condition, then measure	d Vn /Vn ≤ 10% no visible damage	

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Mechanical	Solderability	<u>IEC 68-2-58</u>	At least 95% of terminal
Reliability		Solder bath method, $230 \pm 5^\circ\!\!\!\mathrm{C}$, 2s	electrode is covered by new solder
	Resistance to	IEC 68-2-58	$dVn/Vn \le 5\%$
soldering heat	Solder bath method, $260\pm5\%$, 10 ± 0.5 s, $270\pm5\%$, 3 ± 0.5 s	no visible damage	
	Bending strength	IEC 68-2-21	$dVn /Vn \le 5\%$
		Warp:2mm, Speed:0.5mm/sec, Duration: 10sec. The measurement shall be made with board in the bent position	no visible damage
	Adhesive strength	IEC 68-2-22	Strength>10 N
		Applied force on SMD chip by fracture from PCB	no visible damage

2. Material Specification

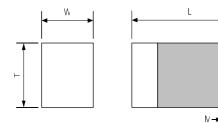
Body ZnO based ceramics

Internal electrode Silver – Palladium

External electrode Silver – Nickel – Tin

Thickness of Ni/Sn plating layer Nickel $> 1 \mu m$, Tin $> 2 \mu m$

3. Dimension Specification

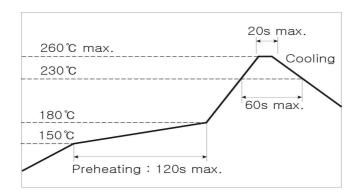


Size	L(mm)	W(mm)	T(mm)	M(mm)
0402	1.0 ± 0.10	0.5 ± 0.10	≤ 0.6	0.20 ± 0.10
0603	1.6±0.15	0.8±0.15	≤ 0.9	0.35 ± 0.10

4. Soldering Recommendations

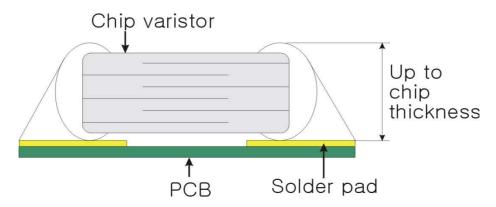
4-1 Soldering profile

4-1-1 Pb free solder paste



4-1-2 Repair soldering

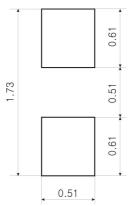
- Allowable time and temperature for making correction with a soldering iron
 : 350 ± 10 °C, 3 sec.
- Optimum solder amount when corrections are made using a soldering iron



4-2 Soldering guidelines

- Our chip varistors are designed for reflow soldering only. Do not use flow soldering
- Use non-activated flux (CI content 0.2% max.)
- Follow the recommended soldering conditions to avoid varistor damage.

4-3 Solder pad layout



5. Storage condition

- Storage environment must be at an ambient temperature of 25~35 $^{\circ}{\rm C}$ and an ambient humidity of 40~60 $^{\circ}{\rm RH}$
- Chip varistors can experience degradation of termination solderability when subjected to high temperature of humidity, or if exposed to sulfur or chlorine gases.
- Avoid mechanical shock (ex. Falling) to the chip varistor to prevent mechanical cracking inside of the ceramic dielectric due to its own weight.
- Use chips within 6 months.
 If 6 months of more have elapsed, check solderability before use.-

6. Description about package label

Type: MVR0603-240E0R2

MVR: Series name

0603 : Chip size -0603 (1.6 x 0.8 mm) size

240 : Maximum continuous working voltage - 24Vdc

E: Product function - E for ESD

0R2: Capacitance value - means 0.2pF

Qunatity: 4,000 pcs

- Quantity of shipping chip varistor